

Space product assurance - Derating - EEE components

Táto norma obsahuje anglickú verziu európskej normy. This standard includes the English version of the European Standard.

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Assurance produit des projets spatiaux - Derating des composants EEE

Raumfahrtproduktsicherung - Herabsetzen/Unterlastung von EEE-Komponenten

This European Standard was approved by CEN on 13 March 2014.

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Table of contents

Foreword6				
Intro	duction	7		
1 Sc	ppe	8		
2 No	mative references	9		
3 Ter	ms, definitions and abbreviated terms	10		
3.1	Terms from other standards	10		
3.2	Terms specific to the present standard	10		
3.3	Abbreviated terms	11		
4 Us	er responsibility	13		
5 Dei	rating	14		
5.1	Overview	14		
5.2	Principles of derating	14		
5.3	Applicability and component selection	15		
5.4	Derating parameters	17		
5.5	Additional rules and recommendations	18		
6 Tal	oles for load ratios or limits	19		
6.1	Overview	19		
6.2	Capacitors: ceramic - family-group code: 01-01 and 01-02	20		
6.3	Capacitors: solid tantalum - family-group code: 01-03	21		
6.4	Capacitors: non-solid tantalum - family-group code: 01-04	22		
6.5	Capacitors: Plastic metallized - family-group code: 01-05	23		
6.6	Capacitors: glass and porcelain - family-group code: 01-06	24		
6.7	Capacitors: mica and reconstituted mica - family-group code: 01-07	25		
6.8	Capacitors: feedthrough - family-group code: 01-10	26		
6.9	Capacitors: semiconductor technology (MOS type) - family-group code: 01-11	27		
6.1	0 Capacitors: miscellaneous (variable capacitors) - family-group code: 01-99	28		
6.1	1 Connectors - family-group code: 02-01, 02-02, 02-03, 02-07 and 02-09	29		
6.1	2 Connectors RF - family-group code: 02-05	30		

6.13	Piezo-electric devices: crystal resonator - family-group code: 03-01	31				
6.14	Diodes - family-group code: 04-01, 04-02, 04-03, 04-04, 04-06, 04-08, 04-10 and 04-14	32				
6.15	Diodes: RF/microwave - family-group code: 04-05, 04-11 to 04-13, 04-15, 04-16 and 04-17	34				
6.16	Feedthrough filters - family-group code: 05-01	35				
6.17	Fuses: Cermet (metal film on ceramic) - family-group code: 06-01	36				
6.18	Inductors and transformers - family-group code: 07-01 to 07-03 and 14-01	37				
6.19	6.19 Integrated circuits: logic - family-group code: 08-10, 08-20, 08-21, 08-29 to 08 42, and 08-80					
6.20	Integrated circuits: non-volatile memories - family-group code: 08-22, 08-23 and 08-24	39				
6.21	Integrated circuits: linear - family-group code: 08-50 to 08-60 and 08-69	40				
6.22	Integrated circuits: linear converters - family-group code: 08-61 and 08-62	41				
6.23	Integrated circuits: MMICs - family-group code: 08-95	42				
6.24	Integrated circuits: miscellaneous - family-group code: 08-99	43				
6.25	Relays and switches - family-group code: 09-01, 09-02 and 16-01	44				
6.26	Resistors - family-group code: 10-01 to 10-11	47				
6.27	Thermistors - family-group code: 11-01 to 11-03	50				
6.28	Transistors: bipolar - family-group code: 12-01 to 12-04 and 12-09	51				
6.29	Transistors: FET - family-group code: 12-05 and 12-06	52				
6.30	Transistors: RF: bipolar - family-group code: 12-10 and 12-13	53				
6.31	Transistors: RF: FET - family-group code: 12-12, 12-14, 12-15(FET) and 12-16(FET)	55				
6.32	Wires and cables - family-group code: 13-01 to 13-03	57				
6.33	Opto-electronics - family-group code: 18-01 to 18-05	59				
6.34	RF passive components: family-group code: 30-01, 30-07, 30-09, 30-10 and 30-99	60				
6.35	Fibre optic components: fibre and cable: family-group-code: 27-01	61				
6.36	Hybrids	62				
Bibliog	ıraphy	68				
Figure	s ·					
Figure 5	5-1: Parameter stress versus strength relationship	15				
Tables						
	Table 6-1: Derating of parameters for capacitors family-group code 01-01 and 01-0220					
	-2: Derating of parameters for capacitors family-group code 01-03					
Table 6	-3: Derating of parameters for capacitors family-group code	22				

EN 16602-30-11:2014 (E)

Table 6-4: I	Derating of parameters for capacitors family-group code 01-05	23
Table 6-5: I	Derating of parameters for capacitors family-group code 01-06	.24
Table 6-6: I	Derating of parameters for capacitors family-group code 01-07	.25
Table 6-7: I	Derating of parameters for capacitors family-group code 01-10	.26
Table 6-8: I	Derating of parameters for capacitors family-group code 01-11	.27
Table 6-9: I	Derating of parameters for capacitors family-group code 01-99	.28
Table 6-10:	Derating of parameters for connectors family-group code 02-01, 02-02, 02-03, 02-07 and 02-09	29
Table 6-11:	Derating of parameters for connectors RF family-group code 02-05	.30
Table 6-12:	Derating of parameters for piezo-electric devices family-group code 03-01	.31
Table 6-13:	Derating of parameters for Diode (signal/switching, rectifier including Schottky, pin)	32
Table 6-14:	Derating of parameters for Diode (Zener, reference, transient suppression)	.32
Table 6-15:	Derating of parameters for Diodes family-group code 04-05, 04-11 to 04-13, 04-15, 04-16 and 04-17	34
Table 6-16:	Derating of parameters for Feedthrough filters family-group code 05-01	.35
Table 6-17:	Derating of parameters for Fuses family-group code 06-01	.36
Table 6-18:	Derating of parameters for Inductors and transformers family-group code 07-01 to 07-03 and 14-01	37
Table 6-19:	Derating of parameters for Integrated circuits family-group code: 08-10, 08-20, 08-21, 08-29 to 08-42, and 08-80	38
Table 6-20:	Derating of parameters for Integrated circuits family-group code: 08-22, 08-23 and 08-24	39
Table 6-21:	Derating of parameters for Integrated circuits family-group code 08-50 to 08-60 and 08-69	40
Table 6-22:	Derating of parameters for Integrated circuits family-group code 08-61 and 08-62	41
Table 6-23:	Derating of parameters for Relays and switches family-group code 09-01, 09-02 and 16-01	45
Table 6-24:	Derating of parameters for Metal film precision resistor (type RNC, except RNC 90)	47
Table 6-25:	Derating of parameters for Metal film semi-precision resistor (type RLR)	.47
Table 6-26:	Derating of parameters for Foil resistor (type RNC 90)	.48
Table 6-27:	Derating of parameters Wire-wound high precision resistor (type RBR 56)	.48
Table 6-28:	Derating of parameters for Wire-wound power resistor (type RWR, RER)	.48
Table 6-29:	Derating of parameters for Chip resistor (RM), network resistor	.49
Table 6-30:	Derating of parameters for Carbon composition resistor	.49
Table 6-31:	Derating of parameters for Heaters	.49
Table 6-32:	Derating of parameters for Thermistors family-group code 11-01 to 11-03	.50
Table 6-33:	Derating of parameters for Transistors family-group code 12-01 to 12-04 and 12-09	51

EN 16602-30-11:2014 (E)

Table 6-37: Derating of parameters for Wires and cables family-group code 13-01 to 13-03	52
15(FET) and 12-16(FET)	54
13-03	55
	57
Table 6-38: Bundle factor K for calculation of the derated current for each individual wire in bundles of N wires	58
Table 6-39: Derating of parameters for Opto-electronics family-group code 18-01 to 18-	59
Table 6-40: Derating of parameters for RF passive components from family-group code 30-01, 30-07, 30-09, 30-10 and 30-99 - Low power < 5 W	60
Table 6-41: Derating of parameters for RF passive components from family-group code 30-01, 30-07, 30-09, 30-10 and 30-99 - Low power \geq 5 W	60
Table 6-42: Derating of parameters for Fibre optic components	61

Foreword

This document (EN 16602-30-11:2014) has been prepared by Technical Committee CEN/CLC/TC 5 "Space", the secretariat of which is held by DIN.

This standard (EN 16602-30-11:2014) originates from ECSS-Q-ST-30-11C Rev 1.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by March 2015, and conflicting national standards shall be withdrawn at the latest by March 2015.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CEN [and/or CENELEC] shall not be held responsible for identifying any or all such patent rights.

This document has been prepared under a mandate given to CEN by the European Commission and the European Free Trade Association.

This document has been developed to cover specifically space systems and has therefore precedence over any EN covering the same scope but with a wider domain of applicability (e.g. : aerospace).

According to the CEN-CENELEC Internal Regulations, the national standards organizations of the following countries are bound to implement this European Standard: Austria, Belgium, Bulgaria, Croatia, Cyprus, Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.

Introduction

This Standard specifies derating requirements applicable to electronic, electrical and electromechanical components.

Derating is a long standing practice applied to components used on spacecrafts. Benefits of this practice are now proven, but for competitiveness reasons, it becomes necessary to find an optimized reliability. Too high a derating can lead to over-design, over-cost and over-sizing of components, the direct consequence being excess volume and weight. The aim is to obtain reliable and high performance equipment without over-sizing of the components. For this reason and if possible, this Standard provides derating requirements depending on mission duration and mean temperature, taking into account demonstrated limits of component capabilities.

1 Scope

This Standard applies to all parties involved at all levels in the realization of space segment hardware and its interfaces.

The objective of this Standard is to provide customers with a guaranteed performance and reliability up to the equipment end-of-life. To this end, the following are specified:

- Load ratios or limits to reduce stress applied to components;
- Application rules and recommendations.

This standard may be tailored for the specific characteristics and constraints of a space project, in accordance with ECSS-S-ST-00.

Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this ECSS Standard. For dated references, subsequent amendments to, or revisions of any of these publications do not apply. However, parties to agreements based on this ECSS Standard are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. For undated references the latest edition of the publication referred to applies.

EN reference	Reference in text	Title
EN 16601-00-01	ECSS-S-ST-00-01	ECSS system - Glossary of terms
EN 16602-60	ECSS-Q-ST-60	Space product assurance - Electrical, electronic and electromechanical (EEE) components
	ESCC 2269010	Evaluation test programme for monolithic microwave integrated circuits (MMICS)
	ESCC 2265010	Evaluation Test Programme for Discrete Microwave Semiconductors

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